

VLSI Design Flow

Solution of Mid Semester Exam (13th March 2022)

Time allowed: 1 hour

Maximum Marks: 30

1. Area of wafer = $\pi r^2 = \pi * 15 * 15 = 706.85 \text{ cm}^2$

Area of die = 0.25 cm²

Number of dies fabricated = $706.85 / 0.25 = 2827$ 1 mark

(a) $A_d = 0.25 * 0.5 = 0.125$

$\text{Yield} = (1 + 0.125 / 0.5)^{-0.5} * 100 = 89.44\%$ 1 mark

Number of good dies = $2827 * 0.8944 = 2528$ 1 mark

Cost per die = $\$200 / 2528 = 7.92$ cents 1 mark

(b) New $A_d = 0.25 * 0.1 = 0.025$

$\text{New Yield} = (1 + 0.025 / 0.5)^{-0.5} * 100 = 97.6\%$ 1 mark

Number of good dies = $2827 * 0.976 = 2758$ 1 mark

Cost per die = 7.24 cents 1 mark

The yield improves because the defect density decreases and less percentage of dies get impacted by the defect. 1 mark

(c) Area of die=1 cm²

Number of dies fabricated = $706.85 / 1 = 706$ 0.5 mark

$A_d = 1 * 0.1 = 0.1$

$\text{New Yield} = (1 + 0.1 / 0.5)^{-0.5} * 100 = 91.3\%$ 1 mark

Number of good dies = $706 * 0.913 = 644$ 0.5 mark

Cost per die = $20000 / 644$ cents = 31.06 cents 1 mark

The yield decreases because with the increased die area, the probability of getting a defect on a die increase. 1 mark

2.

- a. `create_clock -name VCLK -period 1`
`set_input_delay 0.1 -clock [get_clocks VCLK] [get_ports IN]` 0.5+0.5 mark
- b. `set_case_analysis 0 [get_ports TM]`

set_case_analysis 1 [get_ports NORMAL] 0.5+0.5 mark

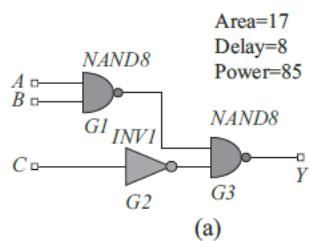
c.

set_multicycle_path 8 -setup -from [get_pins FF1/CP] -to [get_pins FF2/CP]
set_multicycle_path 5 -hold -from [get_pins FF1/CP] -to [get_pins FF2/CP]

1 mark for setup
3 marks for hold
[0 marks if multiplier is wrong in hold]

3.

(a)

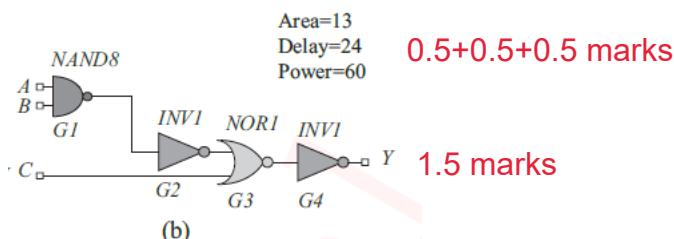


0.5+0.5+0.5 marks for area, delay power calculations

1.5 marks for circuit mapping

(a)

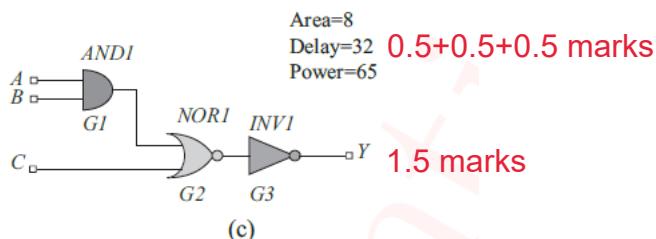
(b)



0.5+0.5+0.5 marks

1.5 marks

(c)



0.5+0.5+0.5 marks

1.5 marks

(c)

(d) (i) (c) has minimum area

(ii) (a) has minimum delay of worst path

(iii) (b) has minimum power

1+1+1 marks